

# HiPerFET™ Power MOSFETs

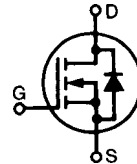
**IXFA 3N80**  
**IXFP 3N80**

$V_{DSS} = 800 \text{ V}$   
 $I_{D25} = 3.6 \text{ A}$   
 $R_{DS(on)} = 3.6 \Omega$

N-Channel Enhancement Mode  
Avalanche Rated, Low  $Q_g$ , High  $dv/dt$

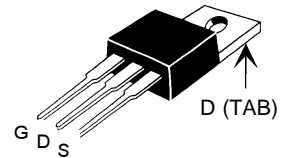
$t_{rr} \leq 250 \text{ ns}$

Preliminary data sheet

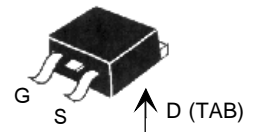


Symbol	Test Conditions	Maximum Ratings	
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	800	V
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1 \text{ M}\Omega$	800	V
$V_{GS}$	Continuous	$\pm 20$	V
$V_{GSM}$	Transient	$\pm 30$	V
$I_{D25}$	$T_C = 25^\circ\text{C}$	3.6	A
$I_{DM}$	$T_C = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	14.4	A
$I_{AR}$	$T_C = 25^\circ\text{C}$	3.6	A
$E_{AR}$	$T_C = 25^\circ\text{C}$	10	mJ
$E_{AS}$		400	mJ
$dv/dt$	$I_S \leq I_{DM}$ ; $di/dt \leq 100 \text{ A}/\mu\text{s}$ ; $V_{DD} \leq V_{DSS}$ ; $T_J \leq 150^\circ\text{C}$ ; $R_G = 2 \Omega$	5	V/ns
$P_D$	$T_C = 25^\circ\text{C}$	100	W
$T_J$		-55 to +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 to +150	$^\circ\text{C}$
$T_L$	1.6 mm (0.063 in) from case for 10 s	300	$^\circ\text{C}$
$M_d$	Mounting torque (TO-220)	1.13/10	Nm/lb.in.
Weight	TO-220	4	g
	TO-263	2	g

TO-220 (IXFP)



TO-263 (IXFA)



G = Gate      D = Drain  
S = Source    TAB = Drain

## Features

- International standard packages
- Low  $R_{DS(on)}$
- Rated for unclamped Inductive load Switching (UIS)

## Advantages

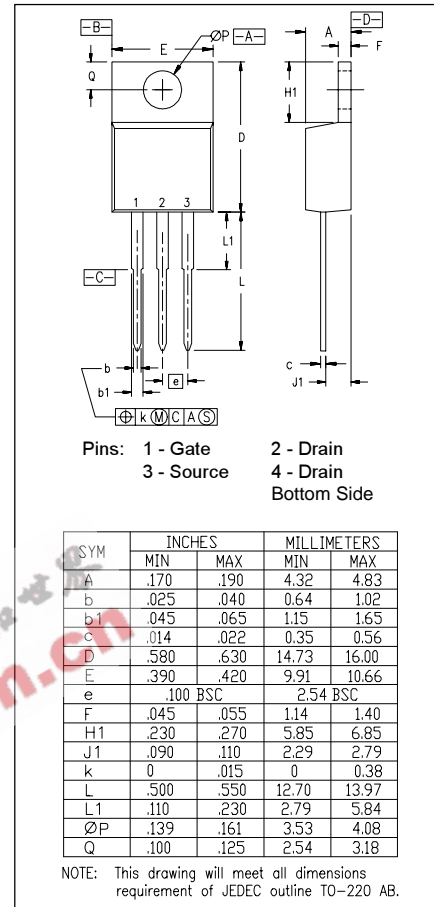
- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		min.	typ.	max.
$V_{DSS}$	$V_{GS} = 0 \text{ V}$ , $I_D = 1 \text{ mA}$	800		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	2.5		V
$I_{GSS}$	$V_{GS} = \pm 20 \text{ V}_{DC}$ , $V_{DS} = 0$			$\pm 100 \text{ nA}$
$I_{DSS}$	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$		50 $\mu\text{A}$
		$T_J = 125^\circ\text{C}$		1 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$ , $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $d \leq 2 \%$			3.6 $\Omega$

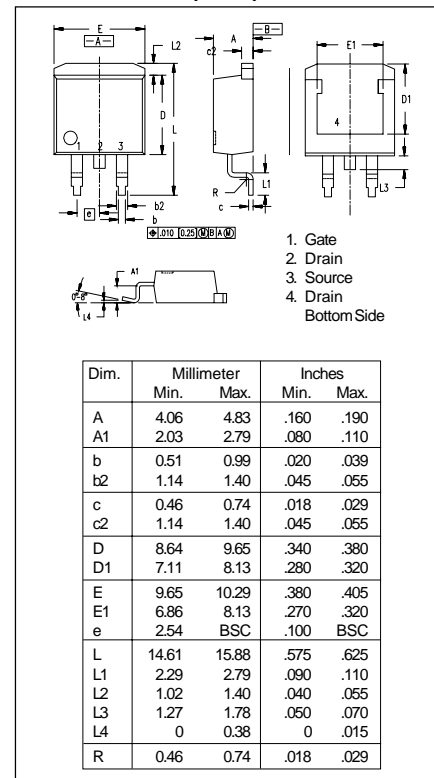
Symbol	Test Conditions	Characteristic Values		
		(T <sub>J</sub> = 25°C, unless otherwise specified)		
		min.	typ.	max.
g <sub>fs</sub>	V <sub>DS</sub> = 20 V; I <sub>D</sub> = 0.5 • I <sub>D25</sub> , pulse test	2.5	3.4	S
C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1 MHz		685	pF
C <sub>oss</sub>			73	pF
C <sub>rss</sub>			16	pF
t <sub>d(on)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 0.5 • V <sub>DSS</sub> , I <sub>D</sub> = 0.5 • I <sub>D25</sub> R <sub>G</sub> = 12 Ω (External),		12	ns
t <sub>r</sub>			11	ns
t <sub>d(off)</sub>			25	ns
t <sub>f</sub>			14	ns
Q <sub>g(on)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 0.5 • V <sub>DSS</sub> , I <sub>D</sub> = 0.5 • I <sub>D25</sub>		24	nC
Q <sub>gs</sub>			6	nC
Q <sub>gd</sub>			9	nC
R <sub>thJC</sub>	(TO-220)		1.25	KW
R <sub>thCK</sub>			0.25	KW

Symbol	Test Conditions	Characteristic Values		
		(T <sub>J</sub> = 25°C, unless otherwise specified)		
		min.	typ.	max.
I <sub>s</sub>	V <sub>GS</sub> = 0 V			3.6 A
I <sub>SM</sub>	Repetitive; pulse width limited by T <sub>JM</sub>			14.4 A
V <sub>SD</sub>	I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			1.5 V
t <sub>rr</sub>	I <sub>F</sub> = I <sub>S</sub> , -di/dt = 100 A/μs, V <sub>R</sub> = 100 V		0.52	250 ns
Q <sub>RM</sub>				μC
I <sub>RM</sub>			1.8	

### TO-220 (IXFP) Outline



### TO-263 (IXFA) Outline



IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715  
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025